

Notice of References Cited	Application/Control No. 10/528,529	Applicant(s)/Patent Under Reexamination VANDER VEEN ET AL.	
	Examiner Nam Huynh	Art Unit 2617	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,046,994	05-2006	Padawer et al.	455/415
*	B	US-6,813,344	11-2004	Lemke, Steve	379/142.06
	C	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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